

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3368	365/201.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:46
L2	3746	365/230.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:46
L3	1692	365/230.08.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:46
L4	280	(normal near3 test\$3) same (burn near5 test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:52
L5	63	4 same memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:47
L6	7	5 same current\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:50
L7	182	(burn near5 test\$3) same (leak\$3 near3 current\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:34
L8	16	7 same ((word adj2 line) or word\$1lin\$2 or "word line")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:53

EAST Search History

L9	57	7 and ((word adj2 line) or word\$1lin\$2 or "word line")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 14:54
L10	12	9 and (stress\$2 adj2 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:19
L11	46	(burn near5 test\$3) same (word adj5 line adj5 driver)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:34
L12	6	11 and PMOS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:34
L13	205	(burn near5 test\$3) and (word adj5 line adj5 driver)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:35
L14	38	13 and PMOS and (high adj3 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:35
L15	32	14 and (low adj3 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:35
L16	22	15 and predetermined	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:35

EAST Search History

L17	1	(switch adj2 circuit) same (normal adj2 data) same (burn adj3 test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:36
L18	21	(switch adj2 circuit) and (normal adj2 data) and (burn adj3 test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:37
L19	21	18 and operation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:37
L20	1	19 and (bit adj3 line adj3 stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:37
L21	21	19 and (bit wit line with stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:37
L22	21	21 and (voltage or power or potential)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:38
L23	25	9 and 1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39
L24	7	9 and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39

EAST Search History

L25	0	9 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39
L26	7	22 and 1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39
L27	0	22 and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39
L28	2	22 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:39
L29	7	22 and 13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:40
L30	1	11 and 22	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:40
L32	1	(memory and (burn adj2 test) and array and (word adj2 line) and (leak\$3 with current\$2) with limit\$2 and (predetermin\$2 with word with line with current) and (stress with voltage) and column). clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:44
L33	1	(method and (word with line with driver) and impedance and (burn with test\$3) and (PMOS with transistor) and source and drain and gate and (word with lin\$2) and predetermin\$3 and (high with voltage) and (low with voltage)). clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:46

EAST Search History

L34	1	((switch with circuit) and (normal with data with path) and (burn with test with path) and (burn with test\$3 with row) and (data with unit) and (bit with line) and (normal with mode) and (read with write with operat\$3) and perform\$3 and (burn with test with mode) and (bit with line with stress with voltage)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 15:49
L35	1	(memory and (burn with test\$3) and (memory with circuit) and array and (word with line) and column and (bit with line) and select\$3 and (switch\$3 with circuit) and (normal with data with path) and (burn with test with path) and row and (word with line with driver\$2) and (PMOS with transistor) and source and gate and drain).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03
L36	0	chou-min.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03
L37	29	chou-min-\$.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03
L38	5	chou-min-chung.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03
L39	1	37 and 9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03
L40	1	37 and 22	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:03

EAST Search History

L41	1	37 and 7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:04
L42	1	37 and 13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:04
L43	1	37 and 4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:04
L44	1	37 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/18 16:04